

<b>Notice of References Cited</b>	Application/Control No. 10/576,766		Applicant(s)/Patent Under Reexamination OVEREND ET AL.	
	Examiner /Susan W. Berman/		Art Unit 1796	Page 1 of 1

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*	B	US-6,402,825	06-2002	Sun, Jing X	106/473
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**NON-PATENT DOCUMENTS**

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